Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/509,402	JAAKOLA, MIKAEL	1
Examiner	Art Unit	
TUAN A. PHAM	2618	

	SEARCHED				
Class	Subclass	Date	Examiner		
455	41.2	4/23/2007	PHAM		
	41.3				
	90				
	344				
	575	4/23/2007	PHAM		
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INTERFERENCE SEARCHED				
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